

CERTIFICATE OF COMPLIANCE

APPLICABLE SPECIFICATIONS:

47 CFR PART 2, SUBPART J, SECTION 2.907 47 CFR PART 15, SUBPART C, SECTION 15.225 INDUSTRY CANADA RADIO STANDARD RSS-210 ISSUE 5

Report Number: 2501-1, Dated 4/20/06

I hereby certify that the measurements shown on this report were made in accordance with the procedures of American National Standards Institute (ANSI) Specification C63.4-2003. The voltages conducted along its power leads and electric fields radiated by the equipment listed below meets the Commissions Limits for a Class B RFID Contactless Reader.

Company: SCM Microsystems
Street Address: 37400 Kato Road
City, State & ZIP Fremont, CA 94560

Equipment under Test: RFID Contactless Reader

Model Number: PAT 1322/1312

Serial Number: 001

EMCE Engineering, Inc. has been placed on the Federal Communications Commission's list of recognized facilities for Parts 15 and 18 DoC approvals. Per the request of EMCE Engineering, Inc., the facility has been added to the list of those who perform Measurement Services for the public on a fee basis. This list is published periodically and is also available on the FCC World Wide Web. Additionally, EMCE Engineering, Inc. has been approved by the National Institute for Standards and Technology under the NVLAP program (Lab Code 200092-0). The Line Conducted emissions (CFR 47, 15.109) results presented in this report fall under EMCE's Scope of Accreditation.

Certified By:

President EMCE Engineering

Date: 4/20/06 Page: 2 of 44

Disclaimer

EMCE Engineering, Inc., assumes no responsibility for the continuing validity of test data when the Equipment under Test is not under the continuous physical control of EMCE. The signature below attests to the fact that all measurements reported herein were performed by myself or were made under my supervision, and are correct to the best of my knowledge and belief as of the date specified. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them. Tests were conducted by qualified EMCE Engineering, Inc. personnel utilizing test equipment maintained in a "current" state of calibration with traceability to NIST.

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Date: 4/20/06 Page: 3 of 44

ELECTROMAGNETIC INTERFERENCE TEST REPORT

Report Number: 2501-1 Report Date: 4/20/06 Applicable Specification:

47 CFR Part 15, Subpart C, Section 15.225 Certification of a Class B RFID Contactless Reader

FCC ID: MBPPAT1322-0300

Equipment under Test: RFID Contactless Reader

Model Number: PAT 1322/1312

Serial Number: 001

Prepared for: SCM Microsystems

37400 Central Court Newark, CA 94560

Tested by: Scott Parr

Prepared by: Bob Cole

EMCE Engineering, Inc. 44366 S. Grimmer Blvd. Fremont, CA 94538 Phone: 510-490-4307 Fax: 510-490-3441

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Date: 4/20/06 Page: 4 of 44

TABLE OF CONTENTS

Paragraph	<u>Title</u>	Page
1.0	SCOPE	5
1.1	<i>Objective</i>	5
1.2	Description of EUT	5
1.3	Results/Modifications	5
1.4	Test Limits	5
2.0	APPLICABLE DOCUMENTS	6
2.1	FCC Document	6
2.2	Other Documents	6
3.0	GENERAL SETUP AND TEST CONDITIONS	7
3.1	Test Facility	7
3.2	Description of Open- Field Test Site	7
3.3	Site Attenuation	7
3.4	Ground Plane (Ground Screen)	7
3.5	Input Power for EUT	9
3.6	Accessory Equipment Precautions	9
3.7	Ambient Interference	9
3.8	Personnel	9
3.9	Use of Interference Measuring Equipment	10
3.10	Calibration of Measuring Equipment	10
4.0	PREPARATION OF EUT FOR TEST	11
4.1	Identification of EUT	11
4.2	Setup of EUT	11
4.3	Interface and Cabling	13
4.4	Peripherals Connected	13
5.0	DETAILED MEASUREMENTS	14
5.1	Conducted Emissions, Power Leads, 450kHz to 30MHz	14
5.1.1	Test Results	14
5.1.2	Test Instrumentation	15
5.1.3	Recommendations	15
5.2	Radiated Emissions Test, 30MHz to 1000MHz	16
5.2.1	Vertical Polarization Measurements	16
5.2.2	Horizontal Polarization Measurements	17
5.2.3	Test Results	17
5.2.4	Test Instrumentation	17
5.2.5	Recommendations	17

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Date: 4/20/06 Page: 5 of 44

40

LIST OF FIGURES

<u>Figure</u>	<u>Title</u>	<u>Page</u>
1	EMCE Test Site Layout	8
	LIST OF APPENDICES	
<u>Appendix</u>	<u>Title</u>	<u>Page</u>
A	EMI Measurement With the Automatic Spectrum Analyzer	18
В	Measurement Equipment Calibration Certification	22
C	Test Data Sheets	26
D	Intentional Radiator Test Data	29
E	Modification List and Photos	34
F	Certification Labeling and Compliance Information	35
G	Measurement Equipment Error Analysis	38

H

Test Equipment List

Date: 4/20/06 Page: 6 of 44

1.0 SCOPE

This test report describes the equipment setup, test methods employed and results obtained during electromagnetic interference (EMI) testing of a Class B RFID Contactless Reader as defined in Part 15, Subpart A, paragraph 15.3 (o). The tests described herein measured the RF radiated (RFI Field Strength) emissions of the equipment under test (EUT) as installed in a typical "Host" environment. The tests conformed to the measurement and test site requirements of ANSI C63.4-2003.

1.1 Objective

The tests described herein were performed to establish that the EUT is capable of compliance with the requirements of Part 15, Subpart B, Section 15.225 for Intentional Radiators (a Class B RFID Contactless Reader).

1.2 Description of EUT

The EUT is a **RFID** Contactless Reader Model Number: **PAT** 1322/1312 Serial Number: **001**, manufactured by SCM Microsystems. The EUT contained the following options: No Options.

Model Differences:

The PAT 1322 has the pinpad installed. The PAT 1312 does not incorporate the pinpad.

All testing was performed on the PAT 1322 unit with the pinpad installed.

1.3 Results/Modifications

The EUT passed FCC Class B conducted and radiated emissions tests. No modification was necessary. The manufacturer may declare the EUT as complying with the FCC requirements.

1.4 Test Limits

FCC Class B Line Conducted and Unintentional Radiated emission limits are as follows:

Conducted Emission Limits (Quasi-peak) Radiated Emission Limits @3-meters

Report Number: 2501-1 4/20/06

			Date.	- 7/20/00
			Page:	7 of 44
0.450 - 30 MHz	48 dBuV	$30-88\mathrm{MHz}$	40.0 dBu	V/m
		88 – 216 MHz	43.5 dBı	uV/m
		216 - 960 MHz	46.0 dBt	uV/m
		960 – 1000 MHz	54.0 dBı	uV/m

Note: In accordance with paragraph 15.107(e) and 15.109(g), CISPR 22 Class B limits are acceptable as an alternate to FCC Class B limits for conducted and radiated emissions.

2.0 APPLICABLE DOCUMENTS

2.1 FCC Documents

Document	<u>Title</u>
Title 47 CFR	TELECOMMUNICATION
Part 2	Frequency Allocations and Radio Treaty Matters; General Rules and Regulations.
Part 15	Radio Frequency Devices.
2.2 Other Documents	
ANSI C63.4-2003	American National Standards for Methods of Measurement of Radio-Noise Emissions From Low-Voltage Electrical and Electronic Equipment In the Range of 9kHz to 40GHz.
ANSI C63.5-1988	American National Standards for Calibration of Antennas Used for Radiated Emissions Measurement.
CISPR 22: 2003	Information technology equipment – Radio disturbance characteristics – Limits and methods of measurement. By the International Electrotechnical Commission (IEC).

Date: 4/20/06 Page: 8 of 44

3.0 GENERAL SETUP AND TEST CONDITIONS

3.1 Test Facility

The tests described herein were performed at:

EMCE Engineering, Inc. 44366 S. Grimmer Blvd. Fremont, CA 94538

This laboratory has one semi-anechoic chamber, one electromagnetic shielded enclosure and a 3-meter and 10-meter Open Area Test Site (OATS). A computer controlled spectrum analyzer with quasi-peak adapter, and printer were used for gathering and recording test data. Figure 1 shows the test site layout for conducted and radiated measurements.

3.2 Description of Open Area Test Site (OATS)

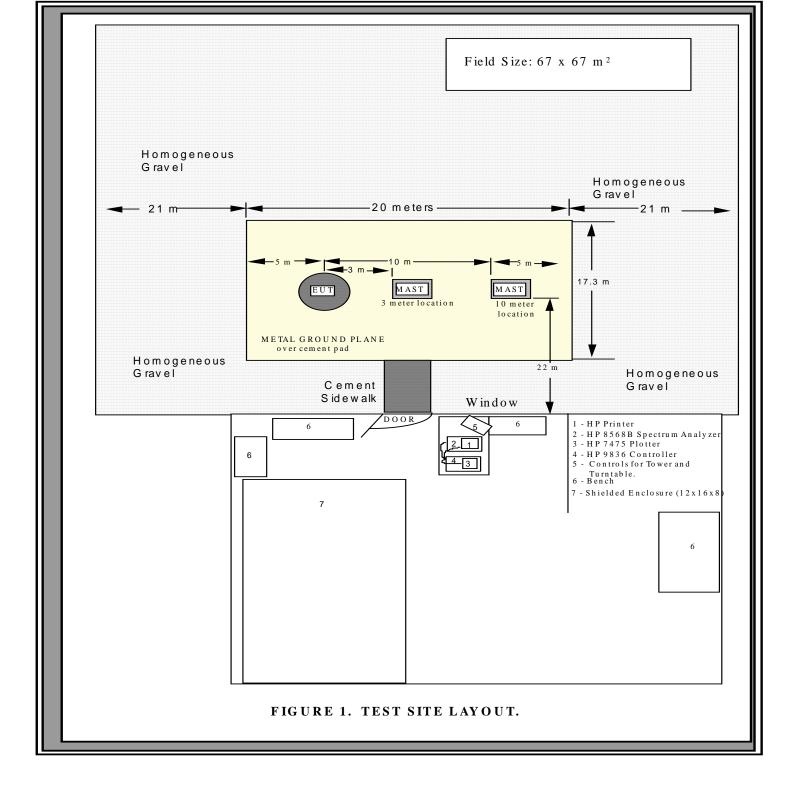
The 3 and 10 meter site is located out-of-doors in an open field whose size is 212 feet long by 206 feet wide. The dimensions of the test area are 66 feet wide by 59 feet long (20m x 18m). The description of the 3 and 10-meter site is on file with the FCC according to the requirements of Part 2.948.

3.3 Site Attenuation

The site attenuation for radiated measurements has been determined for this test site using the method described in ANSI C63.4 Paragraph 5.4.6 and sub paragraphs. The site attenuation is measured annually. Site attenuation was last measured and reported to the FCC in January 2005.

3.4 Ground Plane (Ground Screen)

The site has a 3900 square foot $(20m \ x \ 18m)$ floor area of poured reinforced concrete, 6 to 8 inches thick. A 20m x 18m (66ft x 59ft) solid 24 gauge galvanized sheet steel ground plane is centered on the test area with its long dimension along the major axis of the test site. The antenna mast and turntable are located 3 meters apart on the centerline of the major axis so that each is greater than 3 meters from the edges of the ground plane. The ground plane is connected to a nine-foot long earth ground rod at each corner of the ground plane.



Date: 4/20/06 Page: 10 of 44

3.5 Input Power for EUT

Electricity for the EUT is provided through buried power lines in metallic conduit with an outlet box placed near the EUT. Power for the EUT is taken from the outlet box of either of two "shielded enclosure" quality power line filters located on the ground plane near the EUT. The filters are electrically bonded to the ground plane.

3.6 Accessory Equipment Precautions

Care was taken that accessory equipment or adjacent equipment did not produce unacceptable interference so as to contaminate the final test data. The EMI receiver and its associated computer, printer and plotter were located greater than 15 meters away from the EUT during testing and were powered from a separately filtered power source.

3.7 Ambient Interference

Ambient interference from radio and television stations, vehicles, mobile radio, etc. was present at the open test site during testing. Care was taken to assure that ambient interference did not overload the measurement receiver or mask emissions from the EUT. The method of measurement used to deal with ambient noise during radiated emission testing is described in Paragraph 5.2.1.

3.8 Personnel

All testing was performed by EMCE Engineering personnel who are properly trained for the instruments and procedures used. The test data sheets have been signed-off by the attending EMCE Test Engineer.

Date: 4/20/06 Page: 11 of 44

3.9 Use of Interference Measurement Equipment

All of the emission measurements and field strength measurements were performed with a Hewlett-Packard 8566B Spectrum Analyzer System. The Spectrum Analyzer System utilizes the following basic instruments:

- 1. Fujitsu Lifebook Computer
- 2. EMITest measurement software
- 2. HP-85650A Quasi Peak Adapter

Test results are recorded on tabular data sheets and show final corrected values compared to the specification limit. Sample calculations show how the antenna factors, cable losses, amplifier gain, etc. are combined in the automatic analyzer program to produce the final corrected values shown on the graphs and data sheets.

3.10 Calibration of Measuring Equipment

The EMI Receiver (spectrum analyzer) is calibrated by an outside calibration laboratory on a 12-month basis. The laboratory provides certification with traceability to NIST. Antenna factors are measured at 1-year interval by EMCE Engineering using the reference antenna method of ANSI C63.5-1988. Cable losses as well as amplifier gains are swept at least every month to verify accurate values.

Date: 4/20/06 Page: 12 of 44

4.0 PREPARATION OF EUT FOR TEST

4.1 Identification of EUT

Equipment under Test: RFID Contactless Reader

Model Number: PAT 1322/1312

Serial Number: 001

4.2 Setup of EUT

Power to EUT: **Power Supply**Grounding of EUT: **DC Ground**

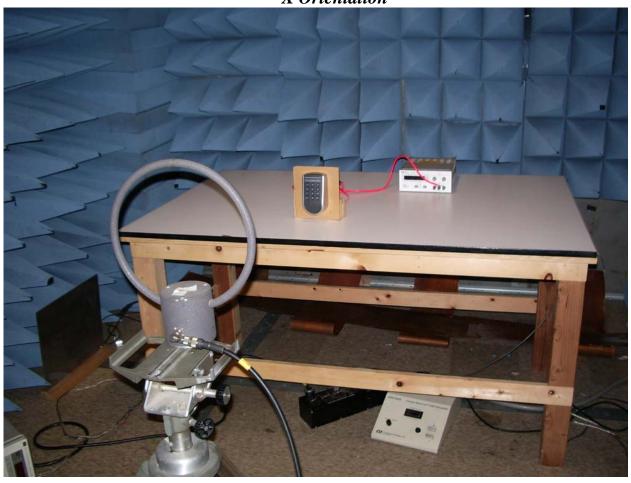
Special Software: None

- Orientation of EUT: Per CFR 47, 15.31 and ANSI 63.4-2003, for all measurements the
- *EUT* was evaluated in the X, Y, and Z orthogonal axes.
- Loop Antenna was manipulated to find the worst case emission. Positions include, but not limited to parallel and perpendicular to the EUT, and parallel to the ground

Date: 4/20/06 Page: 13 of 44

TEST SETUP ORIENTATIONS

X Orientation



Date: 4/20/06 Page: 14 of 44

Y Orientation



Date: 4/20/06 Page: 15 of 44

Z Orientation



Date: 4/20/06 Page: 16 of 44

4.3 Interfaces & Cabling

The following cables were connected during test:

Interface	Source	Load	Length	Conductors	Cable	Connector
	<u>Port</u>	<u>Port</u>	<u>Cable</u>	<u>Number</u>	<u>Type</u>	<u>Material</u>
Power	DC	EUT	<i>1M</i>	3	Unshielded	Plastic
	Power Sup	oply				

4.4 Peripherals

The following peripherals were attached and operating during the tests:

 ${Nomenclature} \over N/A$ ${Mfgr \& Model} \over {Serial No}$

Date: 4/20/06 Page: 17 of 44

5.0 TEST PROCEDURES

5.1 Conducted Emissions, Power Leads, 150 kHz to 30 MHz

Conducted emissions were measured from 150kHz to 30MHz on the power and return leads of the EUT according to the methods defined in ANSI C63.4, Section 7.0 and the limits found in CFR 47, 15.107. The EUT was placed on a nonmetallic stand in a shielded room 0.8 meters above the ground plane and removed from the vertical ground plane by 40-cm as shown in Appendix D, Photographs of Test Setup. The interface cables and equipment positioning were varied within limits of reasonable application per Figure 9A of ANSI C63.4 to determine the position producing maximum conducted emissions.

The LISN and high pass filter were connected through 20 feet of RG-214 coaxial cable to the spectrum analyzer input. The switch on the LISN was set to the Supply Line position and the power was applied. The EUT was operated as described in Paragraph 4.0 in a mode, which was intended to produce maximum emissions for normal operation.

The switch in the LISN was then set to the Return Line position and the interference scan was repeated and an additional set of data sheets and plot charts were prepared for the return lead.

5.1.1 Test Results

Not Applicable due to product type.

5.1.2 Test Instrumentation

See Appendix I - 1,2,3,4,10

5.1.3 Recommendations

Due to the fact that there were no test failures, there are no recommendations.

Date: 4/20/06 Page: 18 of 44

5.2 Radiated Emissions Test, 30 MHz to 1000 MHz

Radiated emissions were measured from 30 MHz to 1000 MHz. The measurement bandwidth was 120 kHz according to the methods defined in ANSI C63.4 Section 8.0. The EUT was placed on a nonmetallic stand in the open-field site, 0.8 meters above the ground plane, as shown in Appendix D, Photographs of Test Setup.

The EUT was operated as described in Paragraph 4.0, in a mode, which was intended to produce maximum emissions. Preliminary scans of the frequency range were used to determine the cable configurations and equipment positions which produce maximum emissions. These configurations were then kept intact while both angle of rotation of the EUT with respect to the antenna and antenna height were scanned for maximum readings. The angles and antenna polarization are shown on the data sheets in Appendix C.

5.2.1 Vertical Polarization Measurements

Radiated emission measurements were started with the antenna in a vertical orientation at 1.5 meter in height and 1.0 meters from the EUT and with the front of the EUT facing the antenna. The measurement antenna was connected to the preamplifier and spectrum analyzer through 75 feet of RG-214 coaxial cable.

A data sheet is printed out listing the "Final FCC B Radiated Results". This lists those signals which were within X dB of the limit, where is selectable and which were actually attributed to the EUT. Along with other information the data sheet indicates signal level, limit, turntable angle and antenna height.

Data sheets of vertical polarized radiated emissions are shown in Appendix C. A sample-calculation on the data sheet shows how antenna factors, cable loss and amplifier gains are processed by the computer.

5.2.2 Horizontal Polarization Measurements

The full electric field frequency range from 30 MHz to 1000 MHz was scanned with the EUT operating and the measurement antenna oriented in a horizontal polarization. A set of radiated emission readings were collected, evaluated, stored and printed out using the same procedure described above for vertical polarization. The data sheets are contained in Appendix C.

Date: 4/20/06 Page: 19 of 44

5.2.3 Test Results

The EUT passed both vertical and horizontal radiated emissions tests.

5.2.4 Test Instrumentation

See Appendix I – 1-10

5.2.5 Recommendations

Because there were no test failures, there are no recommendations.

Date: 4/20/06 Page: 20 of 44

APPENDIX A

Certifications

EMCE NVLAP Accreditation

Date: 4/20/06 Page: 21 of 44

Date: 4/20/06 Page: 22 of 44



National Voluntary Laboratory Accreditation Program



SCOPE OF ACCREDITATION TO ISO/IEC 17025:1999

Universal Compliance Labs dba EMCE Engineering

44366 South Grimmer Boulevard Fremont, CA 94538-6385 Mr. Bob Cole

Phone: 510-490-4307 Fax: 510-490-3441 E-Mail: bob@universalcompliance.com URL: http://www.universalcompliance.com

ELECTROMAGNETIC COMPATIBILITY AND TELECOMMUNICATIONS

NVLAP LAB CODE 200092-0

NVLAP Code Designation / Description

Emissions Test Methods:

12/CIS22 IEC/CISPR 22 (1997) & EN 55022 (1998) + A1(2000): Limits and methods of measurement

of radio disturbance characteristics of information technology equipment

12/CIS22a IEC/CISPR 22 (1993) and EN 55022 (1994): Limits and methods of measurement of radio

disturbance characteristics of information technology equipment, Amendment 1 (1995) and

Amendment 2 (1996)

12/CIS22b CNS 13438 (1997): Limits and Methods of Measurement of Radio Interference

Characteristics of Information Technology Equipment

12/FCC15b1 ANSI C63.4 (2003) with FCC Method 47 CFR Part 15, Subpart B: Unintentional Radiators

12/T51a AS/NZS CISPR 22 (2004): Information technology equipment - Radio disturbance

characteristics - Limits and methods of measurement

Immunity Test Methods:

12/I01 IEC 61000-4-2, Ed. 1.2 (2001) + A1, A2; EN 61000-4-2: Electrostatic Discharge Immunity

Test

12/I03 IEC 61000-4-4(1995), A1(2000), A2(2001); EN 61000-4-4: Electromagnetic compatibility

(EMC) - Part 4-4: Testing and measurement techniques - Electrical Fast Transient/Burst

Immunity Test

2006-01-01 through 2006-12-31

Effective dates

For the National Institute of Standards and Technology

Page 1 of 2

NVLAP-01S (REV. 2005-05-19)

Date: 4/20/06 Page: 23 of 44



National Voluntary Laboratory Accreditation Program



ELECTROMAGNETIC COMPATIBILITY AND TELECOMMUNICATIONS

NVLAP LAB CODE 200092-0

NVLAP Code	Designation / Description
12/I04	IEC 61000-4-5, Ed. 1.1 (2001-04); EN 61000-4-5: Electromagnetic compatibility (EMC) - Part 4-5: Testing and measurement techniques - Surge immunity test
12/I05	IEC 61000-4-6, Ed. 2.0 (2003-05); EN 61000-4-6: Electromagnetic compatibility (EMC) - Part 4-6: Testing and measurement techniques - Immunity to conducted disturbances, induced by radio-frequency fields
12/I06	IEC 61000-4-8, Ed. 1.1 (2001); EN 61000-4-8: Electromagnetic compatibility (EMC) - Part 4-8: Testing and measurement techniques - Power frequency magnetic field immunity test
12/I07	IEC 61000-4-11, Ed. 1.1 (2001-03); EN 61000-4-11: Voltage Dips, Short Interruptions and Voltage Variations Immunity Tests

2006-01-01 through 2006-12-31

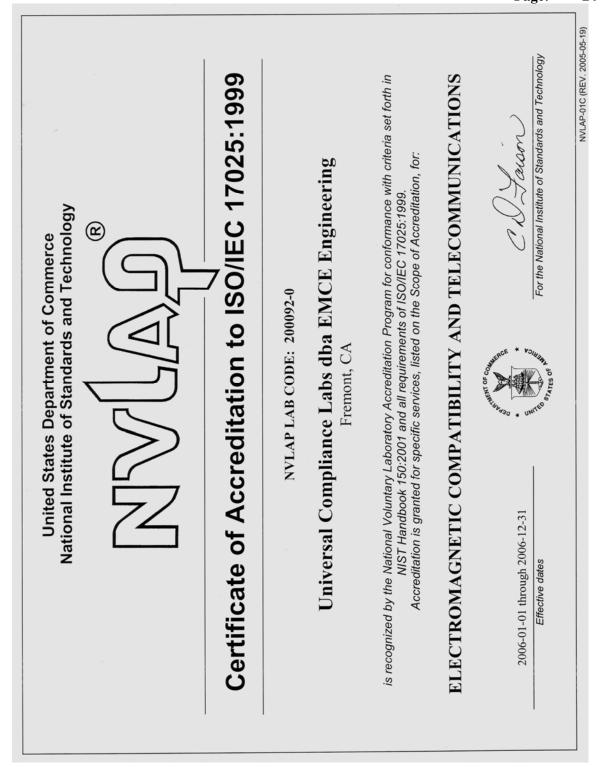
Effective dates

For the National Institute of Standards and Technology

NVLAP-01S (REV. 2005-05-19)

Report Number:

2501-1 Date: 4/20/06 Page: 24 of 44



Date: 4/20/06 Page: 25 of 44

APPENDIX B

Test Data Sheets

Conducted Emissions Radiated Emissions

Date: 4/20/06 Page: 26 of 44

LINE CONDUCTED EMISSIONS TEST

Not Applicable Due to Product Type

Date: 4/20/06 Page: 27 of 44

UNINTENTIONAL RADIATED EMISSIONS TEST

Test Location: EMCE Engineering •44366 S. Grimmer Blvd • Fremont, CA 94538 • 510-490-4307

Customer: SCM Microsystems
Specification: EN55022B RADIATED

Work Order #: 2442 Date: 4/19/2006
Test Type: Radiated Scan Time: 13:21:33
Equipment: Physical Access Reader Sequence#: 4

Equipment: **Physical Access Reader** Sequence#: 4
Manufacturer: SCM Microsystems Tested By: Bob Cole

Model: PAT 1322 S/N: N/A

Test Equipment:

Function S/N		Calibration Date	Cal Due Date	Asset #	
Eauipment Un	der Test (* = EUT):				

Function Manufac

Function	Manufacturer	Model #	S/N	
Physical Access Reader*	SCM Microsystems	PAT 1322	N/A	

Support Devices:

Function	Manufacturer	Model #	S/N	
DC Power Supply	Hewlett-Packard	E3611A	N/A	

Test Conditions / Notes:

Transducer Legend:

T1=AH SAS-200/543 S/N: 199	T2=AH Log P SAS-200_510 S-N853
T3=EMCE Y1 Cable - Radiated Site	T4=8447 Pre-Amp

Measu	rement Data:	Re	eading lis	ted by ma	argin.		Τe	est Distance	e: 10 Meter	rs	
#	Freq	Rdng	T1	T2	Т3	T4	Dist	Corr	Spec	Margin	Polar
	MHz	dΒμV	dB	dB	dB	dB	Table	$dB\muV/m$	$dB\mu V/m$	dB	Ant
1	40.678M	39.5	+12.2	+0.0	+1.2	+26.9	+0.0	26.0	30.0	-4.0	Vert
2	406.800M	39.1	+0.0	+15.0	+4.0	+26.8	+0.0	31.3	37.0	-5.7	Horiz
3	420.360M	37.9	+0.0	+15.7	+3.9	+26.8	+0.0	30.7	37.0	-6.3	Horiz
4	393.240M	38.6	+0.0	+14.6	+3.9	+26.8	+0.0	30.3	37.0	-6.7	Horiz
5	352.560M	39.1	+0.0	+14.4	+3.6	+26.8	+0.0	30.3	37.0	-6.7	Horiz
6	298.318M	35.0	+17.9	+0.0	+3.1	+26.7	+0.0	29.3	37.0	-7.7	Horiz
7	366.120M	37.5	+0.0	+14.5	+3.7	+26.8	+0.0	28.9	37.0	-8.1	Horiz
8	515.261M	32.7	+0.0	+18.2	+3.7	+26.9	+0.0	27.7	37.0	-9.3	Vert
9	433.920M	33.8	+0.0	+16.5	+3.9	+26.8	+0.0	27.4	37.0	-9.6	Horiz
10	447.480M	33.1	+0.0	+17.2	+3.8	+26.8	+0.0	27.3	37.0	-9.7	Horiz
11	325.440M	36.8	+0.0	+13.6	+3.4	+26.8	+0.0	27.0	37.0	-10.0	Horiz

Report Number: Date:

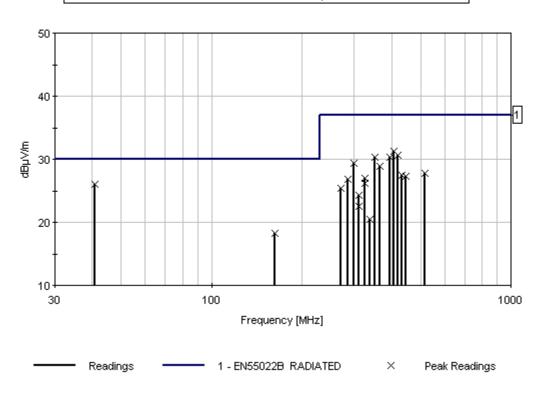
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2501-1 4/20/06

28 of 44

12	284.760M	33.1	+17.4	+0.0	+3.0	+26.7	+0.0	26.8	37.0	-10.2	Vert
13	325.438M	36.0	+0.0	+13.6	+3.4	+26.8	+0.0	26.2	37.0	-10.8	Vert
14	271.200M	32.3	+16.8	+0.0	+3.0	+26.7	+0.0	25.4	37.0	-11.6	Vert
15	162.720M	29.6	+12.8	+0.0	+2.4	+26.6	+0.0	18.2	30.0	-11.8	Vert
16	311.880M	34.8	+0.0	+13.1	+3.2	+26.8	+0.0	24.3	37.0	-12.7	Horiz
17	311.878M	33.1	+0.0	+13.1	+3.2	+26.8	+0.0	22.6	37.0	-14.4	Vert
18	339.000M	29.7	+0.0	+14.0	+3.5	+26.8	+0.0	20.4	37.0	-16.6	Horiz

EMCE Engineering Date: 4/19/2006 Time: 13:21:33 SCM Microsystems WO#: 2442 EN55022B RADIATED Test Distance: 10 Meters Sequence#: 4



Date: 4/20/06 Page: 29 of 44

APPENDIX C

Test Data Sheets Intentional Radiator Results

Date: 4/20/06 Page: 30 of 44

INTENTIONAL RADIATOR

Maximum allowed field strength in the frequency range of 13.553-13.567 MHz is 15,848 microvolts per meter, or 84 dBuV/M at a test distance of 30 meters. Test distance for this measurement is 1 meter. The calculation for determining the field strength limit at 1 meter is as follows:

Correction Factor = 40 log (distance 1 / distance 2) Correction Factor = 40 log (30/1) Correction Factor = 59.1 dBuV/M

Therefore, the limit used for this measurement is 143.1 dBuV/M

The plot on the following page shows the peak power output of the EUT as being 70.9 dBuV/M. at 13.56 MHz, which is the fundamental transmit frequency for this device.

Test results show compliance to the limits called out in CFR 47, Section 15.225 (a), (b), (c), (d) and (e), as well as RSS-210 6.2.2(e) as follows:

Date: 4/20/06 Page: 31 of 44

TEST RESULTS

Peak Output Power

Per CFR 47, Section 15.225 and RSS-210 Issue 5, Section 6.2.2(e)

Test Location: EMCE Engineering •44366 S. Grimmer Blvd • Fremont, CA 94538 • 510-490-4307

Customer: SCM Microsystems

Specification: **RFID Band 13.110-14.010 MHz**

Work Order #: 2501 Date: 4/19/2006
Test Type: Radiated Scan Time: 3:30:23 PM

Equipment: Physical Access Reader Sequence#: 1

Manufacturer: SCM Microsystems Tested By: Bob Cole

Model: PAT 13X2 S/N: N/A

Test Equipment:

Function S/N Calibration Date Cal Due Date Asset #

Equipment Under Test (* = EUT):

Function Manufacturer Model # S/N
Physical Access Reader* SCM Microsystems PAT 13X2 N/A

Support Devices:

Function Manufacturer Model # S/N

Test Conditions / Notes:

RBW = 9 kHz, VBW = 300 kHz

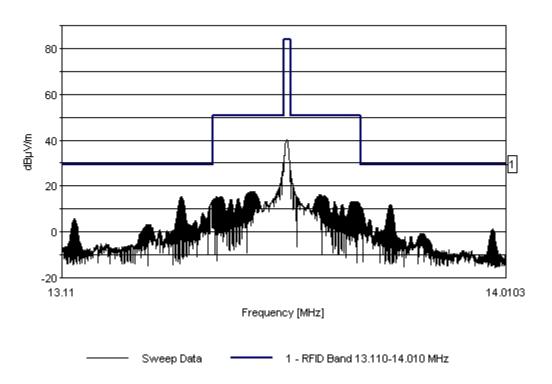
Transducer Legend:

T1=LP-105 Loop Antenna T2=Chamber Receive Cable
T3=8447 Pre-Amp

Measur	ement Data:	Re	eading lis	ted by ma	argin.		Τe	est Distance	e: 1 Meter		
#	Freq	Rdng	T1	T2	T3		Dist	Corr	Spec	Margin	Polar
	MHz	dΒμV	dB	dB	dB	dB	Table	$dB\muV/m$	$dB\mu V/m$	dB	Ant
1	13.346M	51.9	+19.8	+0.7	+27.2		-30.0	15.2	29.5	-14.3	Vert
2	13.347M	51.9	+19.8	+0.7	+27.2		-30.0	15.2	29.5	-14.3	Vert
3	13.348M	51.9	+19.8	+0.7	+27.2		-30.0	15.2	29.5	-14.3	Vert
4	13.344M	51.5	+19.8	+0.7	+27.2		-30.0	14.8	29.5	-14.7	Vert
5	13.343M	50.9	+19.8	+0.7	+27.2		-30.0	14.2	29.5	-15.3	Vert
6	13.350M	50.8	+19.8	+0.7	+27.2		-30.0	14.1	29.5	-15.4	Vert
7	13.409M	50.4	+19.7	+0.7	+27.2		-30.0	13.6	29.5	-15.9	Vert
8	13.550M	64.7	+19.7	+0.7	+27.2		-30.0	27.9	50.5	-22.6	Vert
9	13.547M	60.6	+19.7	+0.7	+27.2		-30.0	23.8	50.5	-26.7	Vert

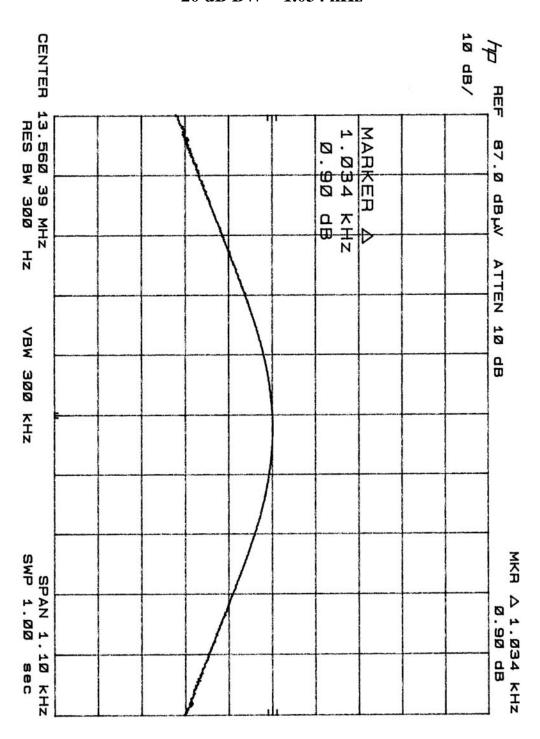
Date: 4/20/06 Page: 32 of 44

EMCE Engineering Date: 4/19/2006 Time: 3:30:23 PM SCM Microsystems WO#: 2501 RFID Band 13:110-14:010 MHz Test Distance: 1 Meter Sequence#: 1



Date: 4/20/06 Page: 33 of 44

20 dB Bandwidth Per RSS-210, Section 5.9.1 20 dB BW = 1.034 kHz



Date: 4/20/06 Page: 34 of 44

Frequency Stability

CFR 47, Section 15.225(e) and Sec 15.31(e), RSS-210 Sec 6.2.2(e) and 6.4

Temperature (Celcius)	Voltage (DC)	Transmit Frequency (MHz)	Upper Limit (MHz)	Lower Limit (MHz)	Pass / Fail
Ambient	12.0	13.550	13.55135	13.54864	PASS
Ambient	10.8	13.549	13.55135	13.54864	PASS
Ambient	13.2	13.550	13.55135	13.54864	PASS
+50	12.0	13.551	13.55135	13.54864	PASS
-20	12.0	13549	13.55135	13.54864	PASS

Date: 4/20/06 Page: 35 of 44

Field Strength of Harmonics

CFR 47, Section 15.225(d), RSS-210 Sec 6.3 Limits from CFR 47, Section 15.209 Test Distance: 3 meters

Frequency (MHz)	Measurement Field strength crovolts/meter)	distance (meters)
(IIII		(meters)
0.009-0.490	2400/F(kHz)	300
0.490-1.705	24000/F(kHz)	30
1.705-30.0	30	30
30-88	100 **	3
88-216	150 **	3
216-960	200 **	3
Above 960	500	3

Test Location: EMCE Engineering •44366 S. Grimmer Blvd • Fremont, CA 94538 • 510-490-4307

Customer: SCM Microsystems
Specification: EN55022B RADIATED

S/N

Work Order #: 2442 Date: 4/19/2006
Test Type: Radiated Scan Time: 13:21:33
Equipment: Physical Access Reader Scy Manufacturer: SCM Microsystems Tested By: Bob Cole

Model: PAT 1322 S/N: N/A

Test Equipment:

Function

Equipment Unde	r Test (* = EUT):	***		
Function	Manufacturar	Model #	S/NI	

Cal Due Date

Asset #

Calibration Date

Function Manufacturer Model # S/N
Physical Access Reader* SCM Microsystems PAT 1322 N/A

Support Devices:

Function	Manufacturer	Model #	S/N
DC Power Supply	Hewlett-Packard	E3611A	N/A

Test Conditions / Notes:

Transducer Legend:

T1=AH SAS-200/543 S/N: 199	T2=AH Log P SAS-200_510 S-N853
T3=EMCE Y1 Cable - Radiated Site	T4=8447 Pre-Amp

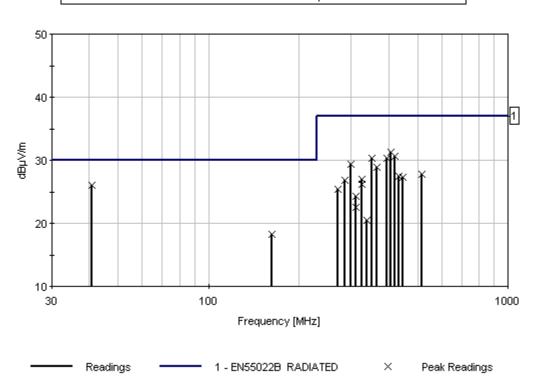
Measur	ement Data:	Reading listed by margin.			Test Distance: 10 Meters						
#	Freq	Rdng	T1	T2	T3	T4	Dist	Corr	Spec	Margin	Polar
	MHz	dΒμV	dB	dB	dB	dB	Table	$dB\muV/m$	$dB\mu V/m$	dB	Ant
1	40.678M	39.5	+12.2	+0.0	+1.2	+26.9	+0.0	26.0	30.0	-4.0	Vert

Report Number: Date: 2501-1 4/20/06

Page: 36 of 44

2	406.800M	39.1	+0.0	+15.0	+4.0	+26.8	+0.0	31.3	37.0	-5.7	Horiz
3	420.360M	37.9	+0.0	+15.7	+3.9	+26.8	+0.0	30.7	37.0	-6.3	Horiz
4	393.240M	38.6	+0.0	+14.6	+3.9	+26.8	+0.0	30.3	37.0	-6.7	Horiz
5	352.560M	39.1	+0.0	+14.4	+3.6	+26.8	+0.0	30.3	37.0	-6.7	Horiz
6	298.318M	35.0	+17.9	+0.0	+3.1	+26.7	+0.0	29.3	37.0	-7.7	Horiz
7	366.120M	37.5	+0.0	+14.5	+3.7	+26.8	+0.0	28.9	37.0	-8.1	Horiz
8	515.261M	32.7	+0.0	+18.2	+3.7	+26.9	+0.0	27.7	37.0	-9.3	Vert
9	433.920M	33.8	+0.0	+16.5	+3.9	+26.8	+0.0	27.4	37.0	-9.6	Horiz
10	447.480M	33.1	+0.0	+17.2	+3.8	+26.8	+0.0	27.3	37.0	-9.7	Horiz

EMCE Engineering Date: 4/19/2006 Time: 13:21:33 SCM Microsystems WO#: 2442 EN55022B RADIATED Test Distance: 10 Meters Sequence#: 4



Date: 4/20/06 Page: 37 of 44

APPENDIX E

EUT MODIFACTION LIST AND PHOTOS

N/A - NO modifications necessary

Date: 4/20/06 Page: 38 of 44

APPENDIX F

CERTIFICATION LABELING AND COMPLIANCE INFORMATION

Date: 4/20/06 Page: 39 of 44

CERTIFICATION LABELING AND COMPLIANCE INFORMATION

If a product must be tested and require Certification, a Compliance Information Statement shall be supplied with the product at the time of marketing or importation. The compliance information statement shall contain the information as shown:

COMPLIANCE INFORMATION STATEMENT

Product Name: RFID Contactless Reader

Product Model Number: PAT 1322/1312

This device complies with Part 15 of the FCC Rules. Operation is subject to the following two conditions: (1) This device may not cause harmful interference, and (2) This device must accept any interference received, including interference that may cause undesired operation.

Identification

Devices subject Certification shall be uniquely identified by the responsible party. This identification shall be of a format consisting of the FCC Identifier, e.g.,:

FCC ID: MBPPAT1322-0300

Labeling Requirements

Product authorizations subject to Certification shall have a label as follows:

The label shall be located in a conspicuous location on the device and shall contain as a minimum the unique identification of "Trade Name" and "Model Number" along with the FCC 2 part statement, as well as the FCC Identifier.

Date: 4/20/06 Page: 40 of 44

Retention of Records

For each product subject to Certification, the responsible party shall maintain the records listed below:

- A) A record of the original design drawings and specifications and all changes that have been made that may affect compliance with the FCC requirements.
- B) A record of the procedures used for production inspection and testing (if tests were performed) to insure the continuous conformance required. (Statistical production line emission testing is not required).
- C) A record of the measurements made on an appropriate test site that demonstrates compliance with the applicable regulations.

Date: 4/20/06 Page: 41 of 44

APPENDIX G

Measuring Equipment Error Analysis

Date: 4/20/06 Page: 42 of 44

MEASURING EQUIPMENT ERROR ANALYSIS

Radiated Emissions Measurement

Table 1 shows the calculated measurement accuracy for radiated emissions test (9kHz-1000MHz). The radiated emissions amplitude accuracy is determined as follows: Antenna Factor Error + Cable Loss Error + Pre-amplifier Gain Error + Spectrum Analyzer Amplitude Error. The spectrum analyzer amplitude error is obtained from the manufacturer's specification sheet. Antenna factors are measured at 1 year intervals by EMCE Engineering, and cable losses as well as amplifier gains are swept at least every month by EMCE Engineering to verify accurate values. The measurement accuracy for these are determined by EMCE.

Table 1
Radiated Emissions Measurement Accuracy

Equipment	Manufacturer	Model	Accuracy
Spectrum Analyzer	Hewlett-Packard	8568B	+/- 1.6dB
Antennas	EMCO/Roberts	<i>3104/Empire</i>	+/- 1.0dB
Pre-amplifier	Hewlett-Packard	8447D	+/- 0.5dB
Double Shielded Coax Cable	50 ohm, Type N	50 feet	+/- <u>0.5dB</u>
			= +/- 3.6dB

Conducted Emissions Measurement

Table 2 shows the calculated measurement accuracy for conducted emissions test (150kHz-30MHz). The conducted emissions amplitude accuracy is determined as follows: LISN Attenuation Error + Cable Loss Error + Spectrum Analyzer Amplitude Error. The spectrum analyzer amplitude error and LISN attenuation error are obtained from the manufacturer's specification sheet. Cable loss below 30MHz is negligible therefore error presented by the cable is not considered.

Table 2
Conducted Emissions Measurement Accuracy

_			
Equipment	<u>Manufacturer</u>	<u>Model</u>	<u>Accuracy</u>
Spectrum Analyzer	Hewlett-Packard	8568B	+/- 1.6dB
LISN	EMCO	3816/2	+/- <u>0.5dB</u>
			= +/- 2.1dB

Date: 4/20/06 Page: 43 of 44

APPENDIX H

TEST EQUIPMENT LIST

Date: 4/20/06 Page: 44 of 44

Test Equipment List

Name	Manufacturer	Model	Cal. Due Date	Designator
Spectrum Analyzer	Hewlett-	8568B	2/1/07	1
	Packard			
Quasi-Peak Adapter	Hewlett-	85650A	2/1/07	2
	Packard			
LISN	EMCO	3816/2	6/15/06	3
Antenna Mast	EMCO	1050	N/A	4
Rotating Table	EMCO	1060	N/A	5
Antenna, Biconical	Electro-Metrics	BIA-30	6/17/06	6
Antenna, Log-periodic	Electro-Metrics	LPA-30	6/17/06	7
Antenna, Loop	Empire Devices	LP-105	6/20/06	8
Preamplifier	Hewlett-	8447D	2/1/07	9
	Packard			
Computer Controller	Fujitsu /	Lifebook	N/A	10
	EMITest			